

Search Notes

Application/Control No.

10/689,983

Examiner

Ernest F. Karlsen

Applicant(s)/Patent under
Reexamination

MATSUMOTO, CHIAKI

Art Unit

2829

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------------------------|-----------|----------|
| 324 | 758 754 765 158.1 | 3/17/2017 | E.F.K. |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|--------------|-----------|----------|
| 324 | 758 158.1 | 3/17/2017 | E.F.K. |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| vacuum same tray same (align or alignment) | 3/17/2017 | E.F.K. |
| tray same semiconductor and test | | |
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